

MOSFET - Dual, N-Channel, POWERTRENCH®, **SyncFET**[™]

FDS6900AS, FDS6900AS-G

General Description

The FDS6900AS is designed to replace two single SO-8 MOSFETs and Schottky diode in synchronous dc-dc power supplies that provide various peripheral voltages for notebook computers and other battery powered electronic devices. FDS6900AS contains two unique 30 V, N-channel, logic level, POWERTRENCH MOSFETs designed to maximize power conversion efficiency.

The high-side switch (Q1) is designed with specific emphasis on reducing switching losses while the lowside switch (Q2) is optimized to reduce conduction losses. Q2 also includes an integrated Schottky diode using onsemi's monolithic SyncFET technology.

Features

- Q2: Optimized to Minimize Conduction Losses Includes SyncFET Schottky Body Diode, 8.2 A, 30 V
 - $R_{DS(on)} = 22 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$
 - $R_{DS(on)} = 28 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$
- Q1: Optimized for Low Switching Losses Low Gate Charge (11 nC typical), 6.9 A, 30 V
 - $R_{DS(on)} = 27 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$
 - $R_{DS(on)} = 34 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$
- 100% R_G (Gate Resistance) Tested
- These Devices are Pb-Free and are RoHS Compliant

Specifications

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

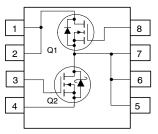
Symbol	Parameter	Q2	Q1	Units
V_{DSS}	Drain-Source Voltage	30	30 30	
V_{GSS}	Gate-Source Voltage	±20 ±20		V
I _D	Drain Current - Continuous (Note 1a) - Pulsed	8.2 30	6.9 20	Α
P _D	Power Dissipation for Dual Operation	1.6 1 0.9		W
	Power Dissipation for Single Operation (Note 1a) (Note 1b) (Note 1c)			
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

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ELECTRICAL CONNECTION



Dual N-Channel SyncFet

MARKING DIAGRAM



FDS6900AS = Specific Device Code = Assembly Site 1 = Wafer Lot Number YW = Assembly Start Week

ORDERING INFORMATION

Device	Package	Shipping [†]
FDS6900AS	SOIC8 (Pb-Free)	2,500 / Tape & Reel
FDS6900AS-G	SOIC8 (Pb-Free)	2,500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

Table 1. ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

	Parameter	Conditions	Type	Min	Тур	Max	Units
OFF CHARA	ACTERISTICS						
BV _{DSS} Di	Drain to Source Breakdown Voltage	I _D = 1 mA, V _{GS} = 0 V	Q2	30			V
		$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	30			
	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, referenced to 25°C	Q2		27		mV/°C
		I_D = 250 μ A, referenced to 25°C	Q1		22		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q2			500	μΑ
			Q1			1	
I_{GSS}	Gate-Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q2			±100	nA
			Q1				
ON CHARA	CTERISTICS (Note 2)						
$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1 \text{ mA}$	Q2	1	1.9	3	V
		$V_{GS} = V_{DS}, I_D = 250 \mu A$	Q1	1	1.9	3	
	Gate to Source Threshold Voltage	I _D = 10 mA, referenced to 25°C	Q2		-3.2		mV/°C
ΔIJ	Temperature Coefficient	I _D = 250 μA, referenced to 25°C	Q1		-4.2		
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 8.2 \text{ A}$	Q2		17	22	$m\Omega$
		$V_{GS} = 10 \text{ V}, I_D = 8.2 \text{ A}, T_J = 125^{\circ}\text{C}$			23	36	
		$V_{GS} = 4.5 \text{ V}, I_D = 7.6 \text{ A}$			21	28	
		$V_{GS} = 10 \text{ V}, I_D = 6.9 \text{ A}$	Q1		22	27	
		$V_{GS} = 10 \text{ V}, I_D = 6.9 \text{ A}, T_J = 125^{\circ}\text{C}$			30	38	
		$V_{GS} = 4.5 \text{ V}, I_D = 6.2 \text{ A}$			27	34	.
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	Q2 Q1	30 20			Α
				20	0.5		
9FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_D = 8.2 \text{ A}$ $V_{DS} = 5 \text{ V}, I_D = 6.9 \text{ A}$	Q2 Q1		25 21		S
DVALA MIC C	NA DA OTERICTIOS	VDS = 3 V, ID = 0.9 A	Qı		21	<u> </u>	
	CHARACTERISTICS				T		_
C_{iss}							
C_{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Q2		570		pF
		$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Q1		600		·
C _{iss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Q1 Q2		600 180		pF pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Q1 Q2 Q1		600 180 150		pF
		V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz	Q1 Q2 Q1 Q2		600 180 150 70		·
C _{oss}	Output Capacitance Reverse Transfer Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Q1 Q2 Q1 Q2 Q1		600 180 150 70 70	40	pF pF
C _{oss}	Output Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Q1 Q2 Q1 Q2 Q1 Q2		600 180 150 70 70 2.8	4.9	pF
C _{oss} C _{rss}	Output Capacitance Reverse Transfer Capacitance Gate Resistance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Q1 Q2 Q1 Q2 Q1		600 180 150 70 70	4.9	pF pF
C _{oss} C _{rss} R _G	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2)		Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2	3.8	pF pF
C _{oss} C _{rss}	Output Capacitance Reverse Transfer Capacitance Gate Resistance	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz V_{DD} = 15 V, I_D = 1 A, V_{GS} = 10 V, R_{GEN} = 6 Ω	Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2	3.8	pF pF
C_{oss} C_{rss} R_{G} SWITCHING $t_{d(on)}$	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2) Turn-On Delay Time	V _{DD} = 15 V, I _D = 1 A, V _{GS} = 10 V,	Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2	3.8 19 18	pF pF Ω
C _{oss} C _{rss} R _G	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2)	V _{DD} = 15 V, I _D = 1 A, V _{GS} = 10 V,	Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2		600 180 150 70 70 2.8 2.2 10 9	3.8 19 18 10	pF pF
C_{oss} C_{rss} R_{G} $t_{d(on)}$ t_{r}	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2) Turn-On Delay Time Turn-On Rise Time	V _{DD} = 15 V, I _D = 1 A, V _{GS} = 10 V,	Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2 10 9 5 4	3.8 19 18 10 8	pF pF Ω ns
C_{oss} C_{rss} R_{G} SWITCHING $t_{d(on)}$	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2) Turn-On Delay Time	V _{DD} = 15 V, I _D = 1 A, V _{GS} = 10 V,	Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2 10 9 5 4 26	3.8 19 18 10 8 42	pF pF Ω
C_{oss} C_{rss} R_{G} $SWITCHING$ $t_{d(on)}$ t_{r}	Output Capacitance Reverse Transfer Capacitance Gate Resistance CHARACTERISTICS (Note 2) Turn-On Delay Time Turn-On Rise Time	V _{DD} = 15 V, I _D = 1 A, V _{GS} = 10 V,	Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1		600 180 150 70 70 2.8 2.2 10 9 5 4	3.8 19 18 10 8	pF pF Ω ns

Table 1. ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Conditions	Type	Min	Тур	Max	Units
WITCHING	G CHARACTERISTICS (Note 2)			-	•	•	
t _{d(on)}	Turn-On Delay Time	V_{DD} = 15 V, I_{D} = 1 A, V_{GS} = 4.5 V, R_{GEN} = 6 Ω	Q2		11	20	ns
,			Q1		10	19	
t _r	t _r Turn-On Rise Time		Q2		15	27	ns
			Q1		9	18	
t _{d(off)}	t _{d(off)} Turn-Off Delay Time	Q2		16	29	ns	
			Q1		14	25	
t _f	Turn-Off Fall Time		Q2		6	12	ns
			Q1		4	8	
Q _{g(TOT)}	Total Gate Charge at V _{GS} = 10 V	Q2: V _{DS} = 15 V, I _D = 8.2 A	Q2		10	15	nC
		Q1: V _{DS} = 15 V, I _D = 6.9 A	Q1		11	15	
Qg	Total Gate Charge at V _{GS} = 5 V		Q2		5.8	8.2	nC
			Q1		6.1	8.5	
Q _{gs}	Gate-Source Charge		Q2		1.6		nC
			Q1		1.7		
Q_{gd}	Gate-Drain Charge		Q2		2.1		nC
			Q1		2.2		
DRAIN-SO	URCE DIODE CHARACTERISTICS AN	ID MAXIMUM RATINGS					
Is	Maximum Continuous Drain-Source		Q2			2.3	Α
	Diode Forward Current		Q1			1.3	
T _{rr}	Reverse Recovery Time	$I_F = 8.2 \text{ A}, d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$	Q2		15		ns
Q _{rr}	Reverse Recovery Charge	(Note 3)			6		nC
T _{rr}	Reverse Recovery Time	$I_F = 6.9 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$	Q1		19		ns
Qrr	Reverse Recovery Charge	(Note 3)			10		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

 $V_{GS} = 0V, I_S = 2.3 A \text{ (Note 2)}$

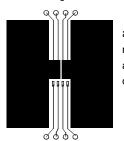
 $V_{GS} = 0V, I_S = 1.3 A \text{ (Note 2)}$

 $V_{GS} = 0V, I_S = 5 A \text{ (Note 2)}$

NOTES:

 V_{SD}

1. R_{6,IA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 78°C/W when mounted on a 0.5 in² pad of 2 oz copper.



b. 125°C/W when mounted on a 0.02 in² pad of 2 oz copper.

c. 135°C/W when mounted on a minimum pad

0.6

0.7

0.7

0.7

1.0

1.2

Q2

Q2

Q1

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.

Drain-Source Diode Forward

Voltage

3. See "SyncFET Schottky body diode characteristics" below.

TYPICAL CHARACTERISTICS: Q2

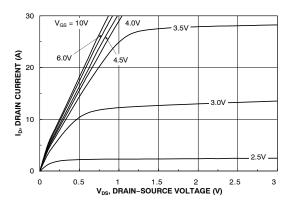


Figure 1. On-Region Characteristics

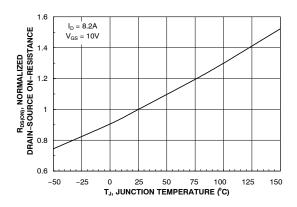


Figure 3. On–Resistance Variation with Temperature

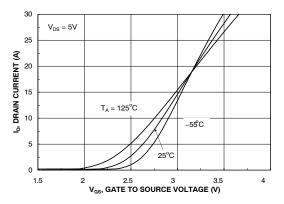


Figure 5. Transfer Characteristics

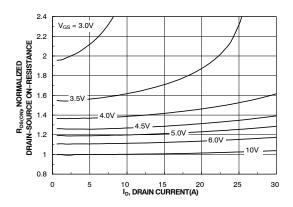


Figure 2. On–Resistance Variation with Drain Current and Gate Voltage

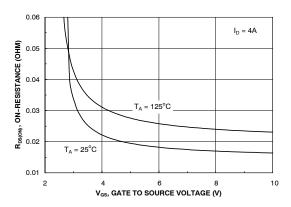


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

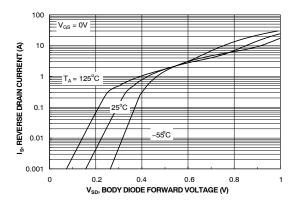


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

TYPICAL CHARACTERISTICS: Q2 (Continued)

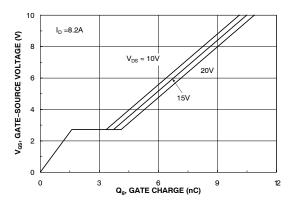


Figure 7. Gate Charge Characteristics

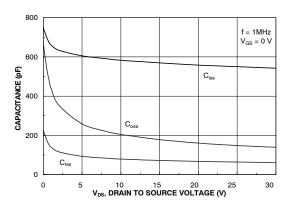


Figure 8. Capacitance Characteristics

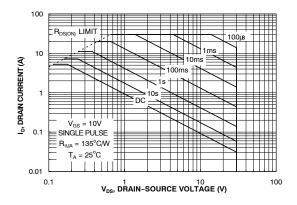


Figure 9. Maximum Safe Operating Area

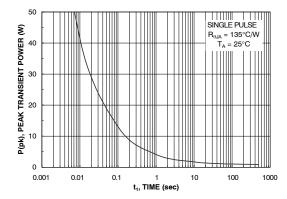


Figure 10. Single Pulse Maximum Power Dissipation

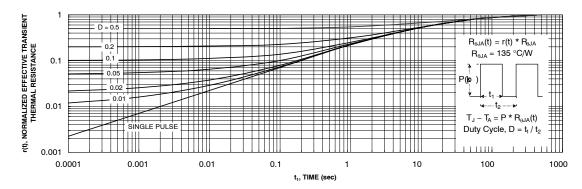


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

TYPICAL CHARACTERISTICS: Q1

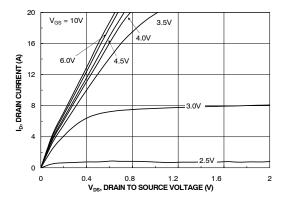


Figure 12. On-Region Characteristics

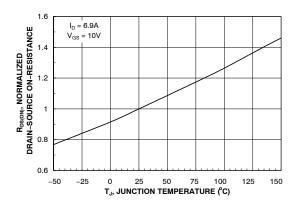


Figure 14. On–Resistance Variation with Temperature

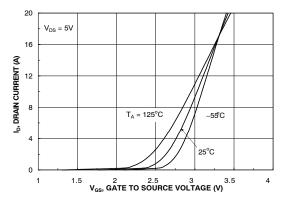


Figure 16. Transfer Characteristics

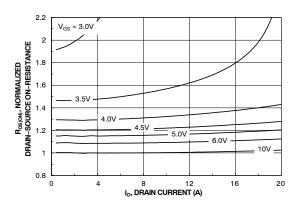


Figure 13. On-Resistance Variation with Drain Current and Gate Voltage

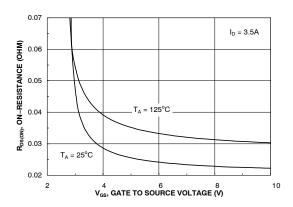


Figure 15. On–Resistance Variation with Gate–to–Source Voltage

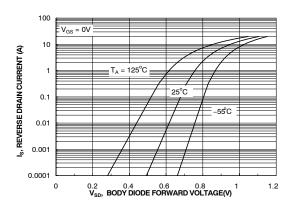


Figure 17. Body Diode Forward Voltage Variation with Source Current and Temperature

TYPICAL CHARACTERISTICS: Q1 (Continued)

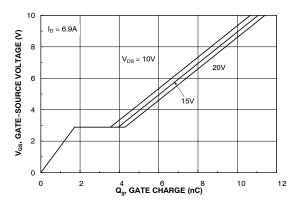


Figure 18. Gate Charge Characteristics

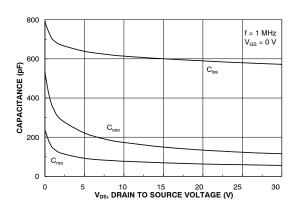


Figure 19. Capacitance Characteristics

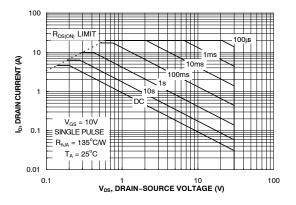


Figure 20. Maximum Safe Operating Area

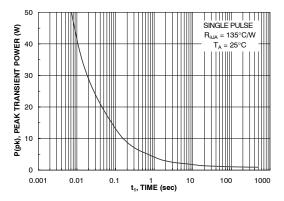


Figure 21. Single Pulse Maximum Power Dissipation

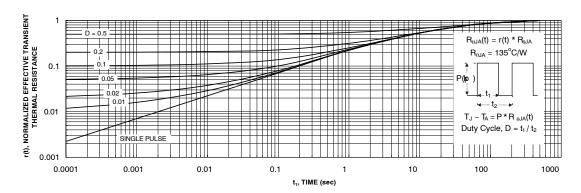


Figure 22. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

TYPICAL CHARACTERISTICS (Continued)

SyncFET Schottky Body Diode Characteristics

onsemi's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 23 shows the reverse recovery characteristic of the FDS6900AS.

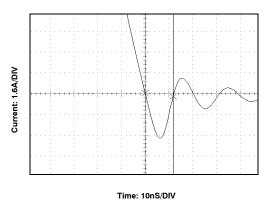


Figure 23. FDS6900AS SyncFET Body Diode Reverse Recovery Characteristics

For comparison purposes, Figure 24 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6690).

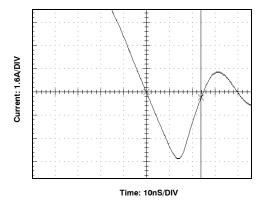


Figure 24. Non-SyncFET (FDS6690) Body Diode Reverse Recovery Characteristics

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

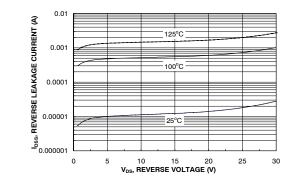


Figure 25. SyncFET Body Diode Reverse Leakage versus Drain-Source Voltage and Temperature

TYPICAL CHARACTERISTICS (Continued)

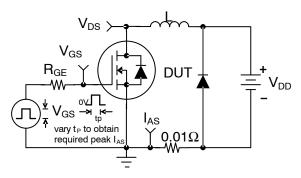


Figure 26. Unclamped Inductive Load Test Circuit

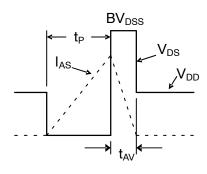


Figure 27. Unclamped Inductive Waveforms

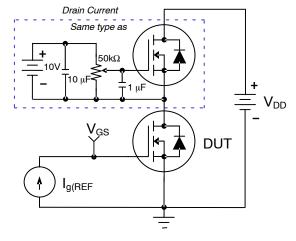


Figure 28. Gate Charge Test Circuit

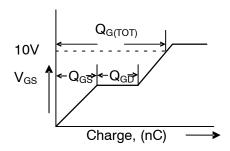


Figure 29. Gate Charge Waveform

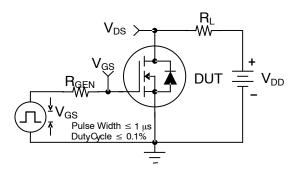


Figure 30. Switching Time Test Circuit

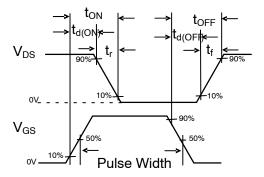


Figure 31. Switching Time Waveform

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CASE 751EB **ISSUE A DATE 24 AUG 2017** ·4.90±0.10 → -0.65(0.635)В 6.00±0.20 5.60 3.90±0.10 PIN ONE **INDICATOR** 1.27 1.27 0.25(M)LAND PATTERN RECOMMENDATION В SEE DETAIL A 0.175±0.075 0.22±0.03 С 1.75 MAX 0.10 0.42±0.09 OPTION A - BEVEL EDGE $(0.43) \times 45^{\circ}$ R0.10 GAGE PLANE OPTION B - NO BEVEL EDGE R0.10-0.25 NOTES: A) THIS PACKAGE CONFORMS TO JEDEC MS-012, VARIATION AA. B) ALL DIMENSIONS ARE IN MILLIMETERS. **SEATING PLANE** C) DIMENSIONS DO NOT INCLUDE MOLD 0.65±0.25 FLASH OR BURRS. D) LANDPATTERN STANDARD: SOIC127P600X175-8M (1.04)**DETAIL** À SCALE: 2:1 Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red. **DOCUMENT NUMBER:** 98AON13735G

SOIC8

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DESCRIPTION:

SOIC8

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